

**LIST OF PATENTS AND PUBLICATIONS**  
**APPLICANT'S INFORMATION**  
**DISCLOSURE STATEMENT**  
 (Form PTO-1449 Modified)



Attorney Docket: 101215-75 Serial No. 09/998,446  
 Applicant: Jörg-Thomas Zettler et al.  
 Filing Date: Nov. 30, 2001 Group: TBA

**U.S. PATENT DOCUMENTS**

Examiner's Initial	Document Number							Date	Name	Class	Sub Class	Filing Date If appropriate	
ML	AA	5	4	0	3	4	3	3	4/1995	P. Morrison, et al.	156	626	
	AB												
	AC												
	AD												
	AE												
	AF												
	AG												
	AH												
	AI												
	AJ												
	AK												

**FOREIGN PATENT DOCUMENTS**

		Document Number		Date	Country	Class	Sub Class	Translation Yes	No
ML	AL	44 19 476	12/1994	Germany					✓
	AM								
	AN								
	AO								
	AP								

**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

ML	AR	Y. Li, et al. Simultaneous in situ Measurement of Substrate Temperature and Layer Thickness Using Diffuse Reflectance Spectroscopy (DRS) During Molecular Beam Epitaxy" Journal of Crystal Growth 175/176 (1997) pgs. 250-255
ML	AS	K.Knorr, et al. "Real-time Monitoring of P-based Semiconductor Growth by Linear-optical Spectroscopy" Eighth International Conference on Indium Phosphide and Related Materials, 1996, IPRM '96, pgs. 590-593
	AT	

EXAMINER:	DATE CONSIDERED:
<i>M.J.L.</i>	<i>Apr. 17, 2003</i>

- EXAMINER: Initial if Reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered, include copy of this form with next communication to applicant.